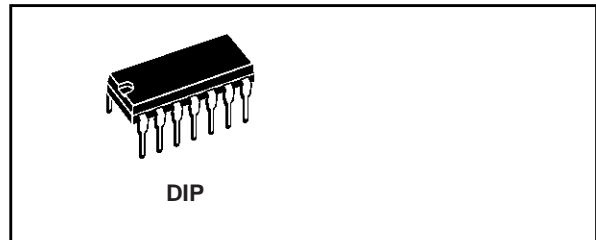




## 8 INPUT NAND/AND GATE

- MEDIUM-SPEED OPERATION  
 $t_{PHL}, t_{PLH} = 75\text{ns}$  (Typ.) at 10V
- BUFFERED OUTPUT
- QUIESCENT CURRENT SPECIFIED UP TO 20V
- 5V, 10V AND 15V PARAMETRIC RATINGS
- INPUT LEAKAGE CURRENT  
 $I_I = 100\text{nA}$  (MAX) AT  $V_{DD} = 18\text{V}$   $T_A = 25^\circ\text{C}$
- 100% TESTED FOR QUIESCENT CURRENT
- MEETS ALL REQUIREMENTS OF JEDEC JESD13B "STANDARD SPECIFICATIONS FOR DESCRIPTION OF B SERIES CMOS DEVICES"



### ORDER CODES

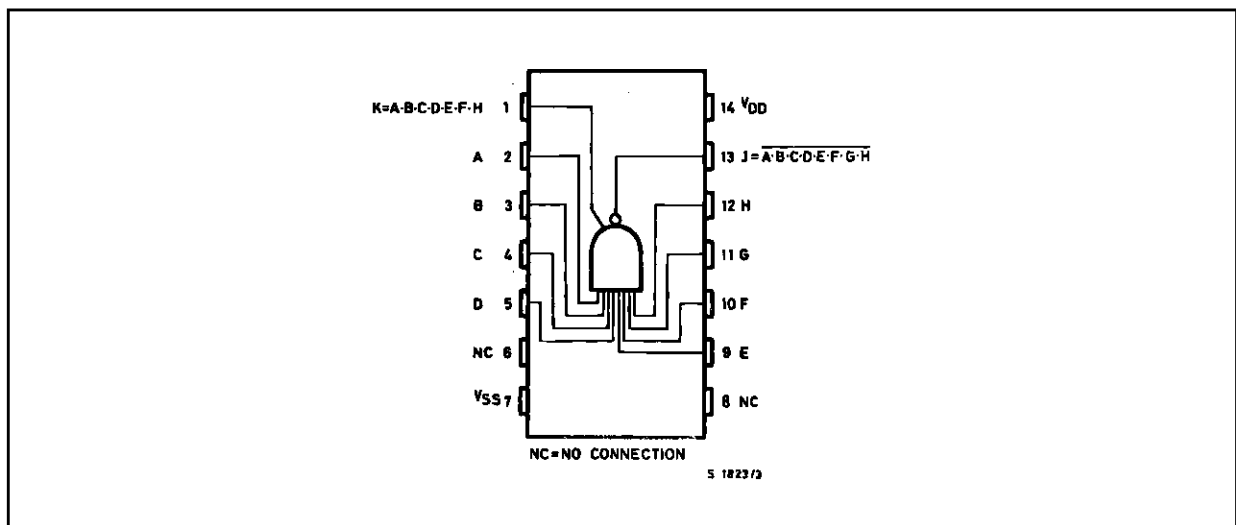
PACKAGE	TUBE	T & R
DIP	CC4068	

### DESCRIPTION

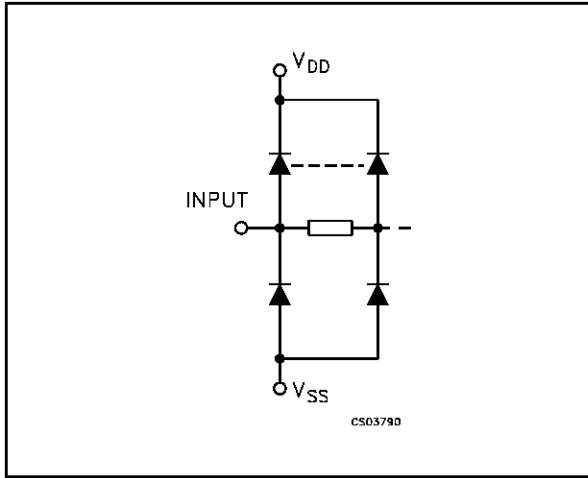
The CC4068 is a monolithic integrated circuit fabricated in Metal Oxide Semiconductor technology available in DIP and SOP packages. The CC4068 8 INPUT NAND/AND GATE provide the system designer with direct

implementation of the positive-logic 8-input NAND and AND functions and supplements the existing family of CMOS gates.

### PIN CONNECTION



INPUT EQUIVALENT CIRCUIT



PIN DESCRIPTION

PIN No	SYMBOL	NAME AND FUNCTION
2, 3, 4, 5, 9, 10, 11, 12	A, B, C, D, E, F, G, H	Data Inputs
6, 8	NC	Not Connected
1	K	Data Output (AND)
13	J	Data Output (NAND)
7	V <sub>SS</sub>	Negative Supply Voltage
14	V <sub>DD</sub>	Positive Supply Voltage

TRUTH TABLES

INPUTS								OUTPUT
A	B	C	D	E	F	G	H	J (NAND)
L	X	X	X	X	X	X	X	H
X	L	X	X	X	X	X	X	H
X	X	L	X	X	X	X	X	H
X	X	X	L	X	X	X	X	H
X	X	X	X	L	X	X	X	H
X	X	X	X	X	L	X	X	H
X	X	X	X	X	X	L	X	H
X	X	X	X	X	X	X	L	H
H	H	H	H	H	H	H	H	L

INPUTS								OUTPUT
A	B	C	D	E	F	G	H	K (AND)
L	X	X	X	X	X	X	X	L
X	L	X	X	X	X	X	X	L
X	X	L	X	X	X	X	X	L
X	X	X	L	X	X	X	X	L
X	X	X	X	L	X	X	X	L
X	X	X	X	X	L	X	X	L
X	X	X	X	X	X	L	X	L
X	X	X	X	X	X	X	L	L
H	H	H	H	H	H	H	H	H

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V <sub>DD</sub>	Supply Voltage	-0.5 to +20	V
V <sub>I</sub>	DC Input Voltage	-0.5 to V <sub>DD</sub> + 0.5	V
I <sub>I</sub>	DC Input Current	± 10	mA
P <sub>D</sub>	Power Dissipation per Package	200	mW
	Power Dissipation per Output Transistor	100	mW
T <sub>op</sub>	Operating Temperature	-55 to +125	°C
T <sub>stg</sub>	Storage Temperature	-65 to +150	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied. All voltage values are referred to V<sub>SS</sub> pin voltage.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Value	Unit
V <sub>DD</sub>	Supply Voltage	3 to 1.8	V
V <sub>I</sub>	Input Voltage	0 to V <sub>DD</sub>	V
T <sub>op</sub>	Operating Temperature	-55 to 125	°C

## DC SPECIFICATIONS

Symbol	Parameter	Test Condition				Value						Unit	
		V <sub>I</sub> (V)	V <sub>O</sub> (V)	I <sub>O</sub>   ( $\mu$ A)	V <sub>DD</sub> (V)	T <sub>A</sub> = 25°C			-40 to 85°C		-55 to 125°C		
						Min.	Typ.	Max.	Min.	Max.	Min.		Max.
I <sub>L</sub>	Quiescent Current	0/5			5		0.01	0.25		7.5		7.5	$\mu$ A
		0/10			10		0.01	0.5		15		15	
		0/15			15		0.01	1		30		30	
		0/18			18		0.02	5		150		150	
V <sub>OH</sub>	High Level Output Voltage	0/5		<1	5	4.95			4.95		4.95		V
		0/10		<1	10	9.95			9.95		9.95		
		0/15		<1	15	14.95			14.95		14.95		
V <sub>OL</sub>	Low Level Output Voltage	5/0		<1	5		0.05			0.05		0.05	V
		10/0		<1	10		0.05			0.05		0.05	
		15/0		<1	15		0.05			0.05		0.05	
V <sub>IH</sub>	High Level Input Voltage		0.5/4.5	<1	5	3.5			3.5		3.5		V
			1/9	<1	10	7			7		7		
			1.5/13.5	<1	15	11			11		11		
V <sub>IL</sub>	Low Level Input Voltage		4.5/0.5	<1	5			1.5		1.5		1.5	V
			9/1	<1	10			3		3		3	
			13.5/1.5	<1	15			4		4		4	
I <sub>OH</sub>	Output Drive Current	0/5	2.5	<1	5	-1.36	-3.2		-1.15		-1.1		mA
		0/5	4.6	<1	5	-0.44	-1		-0.36		-0.36		
		0/10	9.5	<1	10	-1.1	-2.6		-0.9		-0.9		
		0/15	13.5	<1	15	-3.0	-6.8		-2.4		-2.4		
I <sub>OL</sub>	Output Sink Current	0/5	0.4	<1	5	0.44	1		0.36		0.36		mA
		0/10	0.5	<1	10	1.1	2.6		0.9		0.9		
		0/15	1.5	<1	15	3.0	6.8		2.4		2.4		
I <sub>I</sub>	Input Leakage Current	0/18	Any Input		18		$\pm 10^{-5}$	$\pm 0.1$		$\pm 1$		$\pm 1$	$\mu$ A
C <sub>I</sub>	Input Capacitance		Any Input				5	7.5					pF

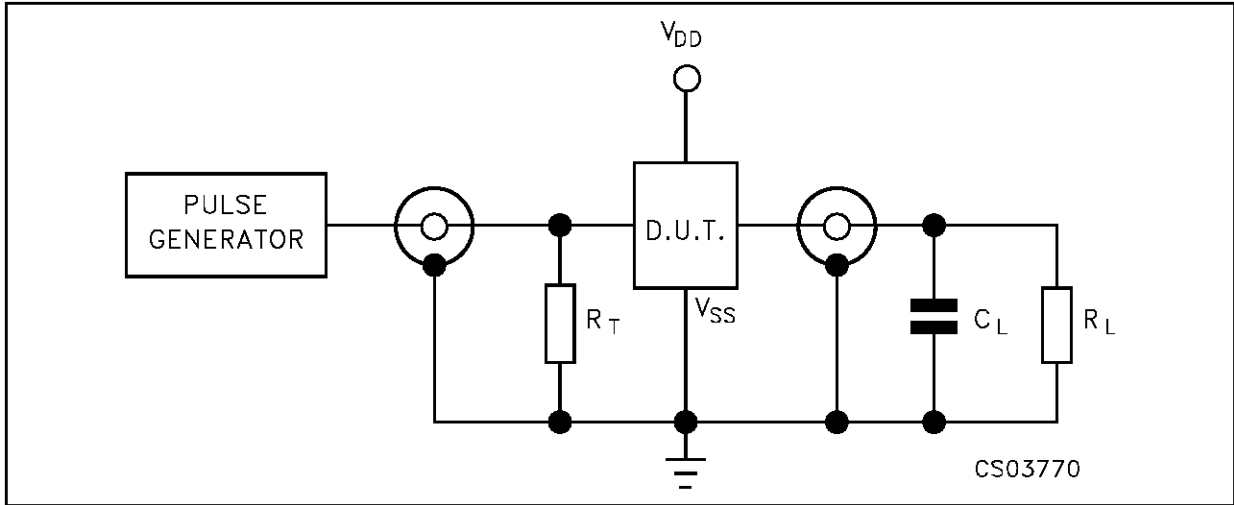
The Noise Margin for both "1" and "0" level is: 1V min. with V<sub>DD</sub>=5V, 2V min. with V<sub>DD</sub>=10V, 2.5V min. with V<sub>DD</sub>=15V

DYNAMIC ELECTRICAL CHARACTERISTICS (T<sub>amb</sub> = 25°C, C<sub>L</sub> = 50pF, R<sub>L</sub> = 200K $\Omega$ , t<sub>r</sub> = t<sub>f</sub> = 20 ns)

Symbol	Parameter	Test Condition		Value (*)			Unit
		V <sub>DD</sub> (V)		Min.	Typ.	Max.	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay Time	5			150	300	ns
		10			75	150	
		15			55	110	
t <sub>TLH</sub> t <sub>THL</sub>	Output Transition Time	5			100	200	ns
		10			50	100	
		15			40	80	

(\*) Typical temperature coefficient for all V<sub>DD</sub> value is 0.3 %/°C.

TEST CIRCUIT



$C_L = 50\text{pF}$  or equivalent (includes jig and probe capacitance)  
 $R_L = 200\text{K}\Omega$   
 $R_T = Z_{OUT}$  of pulse generator (typically  $50\Omega$ )

**WAVEFORM 1 : PROPAGATION DELAY TIMES FOR K OUTPUT (AND FUNCTION) ( $f=1\text{MHz}$ ; 50% duty cycle)**

